

## **An attachment for an optical spectrometer for measuring the concentration profile and coefficient of impurity distribution in a crystal**

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### **Abstract**

An attachment for an optical spectrometer is described enabling automated measurements of the impurity distribution in a crystal. For analysis of the Nd<sup>3+</sup> ion distribution over a LiYF<sub>4</sub> crystal, it is shown that the attachment provides a high resolution when obtaining data on the optical quality of a crystal and the impurity concentration profile and reliably determines the impurity distribution coefficient. © 1997 MAEe cyrillic signK Hayka/Interperiodica Publishing.

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